# Efficient Locality Approximation from Time

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### Locality is Important

- Traditional reasons: memory wall, deeper memory hierarchy.
- New trends: more common and complex cache sharing.



# A Locality Model

- Reuse distance (LRU stack distance)
  - Def: number of distinct elements between reuse [Mattson et. al. 1970]



- Connection with cache
  - Rd > cache size  $\longrightarrow$  a likely cache miss

# Appeal of Reuse Distance

#### More rigorous & machine independent

	Reuse distance		Cache miss rate
Granularity	Point to point	<b>~</b>	Interval
Accuracy	Exact	~	Average
Adaptive to cache sizes	Yes	<b>~</b>	No

# Many Uses in Research

- Study cache reuses [Ding+:SC04,Huang+:ASPLOS05]
- Guide and evaluate program transformation [Almasi+:MSP02, Ding+:PLDI03]
- Predict locality phases [Shen+:ASPLOS04]
- Discover locality-improving refactoring [Beyls+:HPCC06]
- Model cache sharing [Chandra+:HPCA05, Jiang+:EuroPar08]
- Insert cache hints [Beyls+:JSA05]
- Manage superpages [Cascaval+:PACT05]
- Guide memory disambiguation [Fang+:PACT05]
- Predict program performance [Marin+:SIGMETRICS04,Zhong +:TOC07]
- Model reference affinity [Zhong+:PLDI04]

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### Properties of Reuse Distance

	Reuse distance		Cache miss rate
Granularity	Point to point	<b>/</b>	Interval
Accuracy	Exact	V	Average
Adaptive to cache sizes	Yes	~	No
Practical uses	Few		Many 🖌

Our objective: Making reuse distance faster to obtain.

### Outline

- Reuse distance measurement -----
- Efficient approximation of reuse distance (I7X speedup)
  - Algorithmic extensions (I order of magnitude less)
  - Implementation optimizations (3.3X speedup)
- Evaluation tool: trace generator
- Evaluation
- Conclusions

### Previous Research

T: execution time

N: data size



But measuring 1-min execution still takes several hours!

### A Different Path

- Key obstacle: Counting out repetitive references in an arbitrarily long interval.
- Previous methods

implement the definition of reuse distance:

"Counting" distinct data.

 Our approach uses some "cheap" program behavior to statistically approximate reuse distance.

## The "Cheap" Behavior

- Time distance (TD)
  - Def: number of elements between reuse.



- Reuse distance (RD)
  - Def: number of distinct elements between reuse.







# Connection between TD and RD [Shen+:POPL'07]

Expectation of the probability for a variable to appear in a  $\Delta$ -long interval:



Probability for the interval to have k distinct variables (Bernoulli process):

$$p(k, \Delta) = \binom{N}{k} p(\Delta)^k (1 - p(\Delta))^{N-k}$$

## Compute $p(\Delta)$

•  $p(\Delta)$ : a variable to appear in a  $\Delta$ -long interval.

- $p'(\tau)$ : a variable's last access before t is at time  $(t-\tau)$ .  $p(\Delta) = \sum_{\tau=1}^{\Delta} p'(\tau)$ •  $t-\tau$ •  $t-\tau$ • t
- The following is proved in [Shen+:POPL07]  $P'(\tau) = \sum_{\delta=\tau+1}^{T} P_{T}(\delta)/(N-1)$

### Implementation Issues

- Scale: The model applies to every access, but not to histograms.
  - The width of a bar must be 1.
- Overhead: high cost in measuring time distance.
  - Bookkeeping and buffer boundary checking at every memory access.

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### Algorithm Extension

• Basic extension: assume all references in a bar have the same  $p(\Delta)$ , denoted as  $p(b_i)$ .

$$p(\Delta) = \sum_{\tau=1}^{\Delta} \sum_{\delta=\tau+1}^{T} \frac{1}{N-1} P_T(\delta) \longrightarrow \qquad p(b_i) = \sum_{\tau=1}^{\frac{b_i + b_i}{2}} \sum_{\delta=\tau+1}^{T} \frac{1}{N-1} P_T(\delta)$$

$$p(k,\Delta) = \binom{N}{k} p(\Delta)^k (1-p(\Delta))^{N-k} \longrightarrow \qquad p(k,b_i) = \binom{N}{k} p(b_i)^k (1-p(b_i))^{N-k}$$

 $\leftarrow \rightarrow$ 

• Time complexity:  $O(L_T^3)$  $L_T$  : number of bars in a TD histogram.

### Algorithmic Optimizations

• Decompose  $p(b_i)$  into 3 sub-equations to remove redundant computations.

$$p(b_i) = P_2(b_i)/2 + \sum_{j=0}^{i-1} P_2(b_j)$$

$$P_2(b_i) = \left[\sum_{j=i+1}^{L_T} P_1(b_j) \frac{\overrightarrow{b_i} - \overleftarrow{b_i}}{\overrightarrow{b_j} - \overleftarrow{b_j}} \sum_{\tau=\overleftarrow{b_j}}^{\overrightarrow{b_j} - 1} \frac{1}{\tau - 1}\right]$$

$$+ P_1(b_i) \frac{1}{\overrightarrow{b_i} - \overleftarrow{b_i}} \sum_{\tau=\overleftarrow{b_i} + 1}^{\overrightarrow{b_i} - 1} \frac{\tau - \overleftarrow{b_i}}{\tau - 1}$$

$$P_1(b_i) = \frac{\overleftarrow{b_i} + \overrightarrow{b_i} - 3}{2(N - 1)} P_T(b_i).$$

# Algorithmic Optimizations

- Further optimizations
  - mathematical approximation

$$\sum_{i=m_1}^{m_2} \frac{1}{i} \simeq \ln \frac{m_2 + 0.5}{m_1 - 0.5}$$

- statistical approximation
  - Normal distribution with table-lookup for binomial distribution calculation
- Time complexity

$$O(L_T^3) \rightarrow O(L_T^2)$$
  
Details in [Shen+:LCPC'08].

### Measure TD

• Invocation to record function after every load/store.

Basic record function

Procedure RecordMemAcc (addr)
 buffer [index++] = addr;

```
if (index== BUFFERSIZE) then
    ProcessBuff();
endif
```

#### end

After optimization

Procedure RecordMemAcc (addr)
 buffer [index++] = addr;
end

- Fewer operations
- Fewer branch miss predictions
- Amenable to runtime inlining
- 3.3X speedup

### MMU Control

- Typical scheme:
  - Control page permission & modify registers
  - Not portable across architectures.
- Our approach:
  - 2-page scheme
  - Close & open permissions of the final 2 pages alternatively

Details in [Shen+:LCPC'08].

### 2-Page Scheme for Using MMU



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### A Reverse Problem: Trace Generation

• Reuse distance measurement or approximation

Trace  $\longrightarrow$  Reuse distance

• Trace generator

#### Trace - Reuse distance

Use: for evaluating locality techniques on various reuse patterns.



- Technique: a stochastic process
- Property: The generated trace meets input requirements (proof in [Shen+:LCPC'08])

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### Evaluation (Pulse-like reuse distributions)

Time Distance Histogram

Reuse Distance Histogram



### **RD** Approximation on Synthetic Traces

	acc%
Normal (var=20)	92.8
Normal (var=100)	96.3
Normal (var=200)	95.8
Exponential	96.9
Average	95.5

### **Evaluation on Real Benchmarks**

Baseline:	Ding+:PLDI'03.		
Benchmarks	SPEC CPU2000 ref		
HW perf. measure	PAPI 3.2		
Compiler	GCC 3.4.4 ("-O3")		
Instrumentor	PIN 3.4		
CPU	Intel Xeon 2GHz		

### **Results on Real Benchmarks**

Programs	Element	
	acc%	speedup
gcc	89.0	21.2X
gzip	99.0	19.0X
mcf	42.6	8.3X
twolf	88.2	5.9X
ammp	95.8	14.3X
applu	86. I	19.0X
equake	57.6	23.7X
mesa	97.3	26.3X
mgrid	89.7	20.6X
Average	82.8	17.6X

### Uses in Cache Miss Rate Estimation



### Conclusions

- Strong connection exists between time and locality.
- Reuse distance can be approximated from time efficiently.

\* Details in:

"Locality approximation from time", POPL'07. "Adaptive software speculation for enhancing the efficiency of behavior-oriented parallelization", LCPC'08.

# Acknowledgment

- Chen Ding (U of Rochester) suggested the use of 2 pages for MMU control.
- Brian Meeker (U of Rochester) collected preliminary data in the early stage.
- Supported by NSF.